p-type doping of II-V I heterostructures from surface states: application to ferrom agnetic $C d_1 x M n_x Te$ quantum wells

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W e present a study ofp-type doping of C dTe and C d₁ $_{\rm x}$ M n_x Te quantum wells from surface states. W e show that this method is as e cient as usual modulation doping with nitrogen acceptors, and leads to hole densities exceeding 2 10^{11} cm². Surface doping was applied to obtain sam ples with C d₁ $_{\rm x}$ M n_x Te quantum well with up to x = 9:3% containing hole gas. We could also increase the grow th tem perature up to 280 C, which results in sharper photolum inescence lines, when com pared to the sim ilar nitrogen doped sam ples. Carrier-induced ferrom agnetism was observed in surface doped sam ples.

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Studies of carrier induced ferrom agnetism in diluted m agnetic sem iconductors (DMS) are in portant for the developm ent of spintronics - a new eld exploiting spin degrees of freedom for inform ation processing. The most conclusive results have been obtained for p-type doped structures. In III-V DMS, the same impurity (Mn) carries the localized spins and acts as an acceptor [?] which puts strong lim its on the realization of QW s and 2D system s [?] using thin layers of III-V DMS [??]. In Cd_{1 x} M n_xTe quantum wells (QW), it has been proposed theoretically [?] and shown experimentally [?] that the presence of a two dim ensional (2D) carrier gas can induce a ferrom agnetic ordering due to the strong exchange coupling of M n spins to charge carriers. In [?], the modulation-doped structures were grown by molecular beam epitaxy using nitrogen acceptors in the $Cd_{1 y z} Zn_z M g_y Te$ barriers. Although efcient, this method brings certain restrictions. E ective doping of C d_{1 v z} Zn_zM g_vTe with nitrogen is only possible for y lower than 30%, it requires lowering the growth tem perature from the usual 280 C down to 220 C to avoid a strong interdi usion of the heterostructure [?], and thus a ects the quality of the sam ples, e.g., by increasing interface roughness [?]. Moreover the presence of nitrogen precludes alm ost any post-grow th treatm ent of the sam ple.

In this letter we present a method of p-type doping of $Cd_{1 x} Mn_x TeQW$ s from surface states. We show that this method can be ase cient as modulation doping with nitrogen in supplying a hole gas to theQW s, and can be used to induce a ferrom agnetic order in theQW .Furtherm ore it increases the therm all stability of structures allowing grow th and processing of samples at higher temperature. Finally, it makes possible to obtain a hole gas in deeper quantum wells or quantum wells with a higher Mn content.

Sam ples have been grown by molecular-beam epitaxy on two types of (001) substrates, $Cd_{0:88}Zn_{0:12}Te$ which is transparent at the energy of the QW transition, and $Cd_{0:96}Zn_{0:04}Te$. For comparison purposes the growth parameters were rst kept in the range typical for the growth of the nitrogen doped sam ples, including the substrate tem – perature 220 C.Each sam ple contained a 100A wide QW m ade of $Cd_{1 \times}Mn_{x}Te$ or CdTe. The QW was embedded between $Cd_{0:7}Zn_{0:08}Mg_{0:22}Te$ barriers in case of 12% Zn substrate and $Cd_{0:78}Mg_{0:22}Te$ for the sam ples grown on the 4% Zn substrate, so that the whole structure could be

grown coherently strained to the substrate. The thickness of the top barrier was in the range from 150A to 1000A. The barrier on the substrate side was 3000A thick.

All properties discussed below were determined by magneto-optical spectroscopy in the Faraday conguration (magnetic eld perpendicular to the sample surface), with the sample mounted strain-free in liquid helium in a super-conducting magnet. The experimental setup allowed us to perform transmission and relativity studies using a halogen lamp, and photolum inescence (PL) and PL excitation (PLE) using a tunable $A \downarrow O_3$ (T i laser providing about 2 m W /cm². The composition of barriers was checked from the PL transition energy [?]. The Mn content in the QW was checked from tting a modiled Brillouin function [?] to the Zeem an splitting measured in PL.

The rst evidence for the presence of a carrier gas in a QW close to the surface comes from transmission spectra with applied magnetic eld (Fig.1a). Two narrow absorption lines are observed. Their splitting (about 3 m eV) and the strong circular polarization of the low energy line are a ngerprint of a charged exciton transition, and therefore an indication of the presence of a carrier gas [??]

In a CdTeQW subject to a compressive biaxial strain, such as those here which were coherently grown on a $Cd_{0:88}Zn_{0:12}Te$ substrate, the sign of the charge carriers is

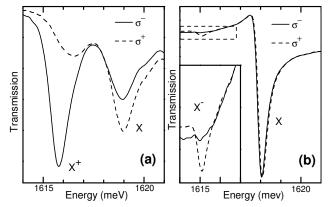


FIG.1: C incularly polarized transm ission spectra, at 3T and 1.7K, for a single CdTe QW with a cap layer thickness of (a) 250A and (b) 1000A. The inset in (b) presents a close-up of the area of the spectrum attributed to a negatively charged exciton. N ote the change in lineshape which is consistent with the change in the cap layer thickness

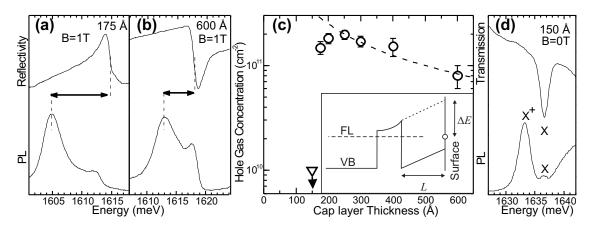


FIG.2: (a), (b) Re ectivity (top) an PL spectra (bottom) at 1.7 K and 1 T for two $Cd_{0.99}M n_{0.01}Te QW$ swith di erent cap layer thicknesses, as indicated. A rrows note the M oss-Burstein shift. (c) Hole density in 100A wide $Cd_{0.99}M n_{0.01}Te QW$ s, determ ined from the M oss-Burstein shift at 1T (circles) or from the charged exciton intensity (triangle, two sam ples). The dashed line is the density expected from surface acceptor states at energy E = 90m eV from the QW state (m odel schem atized in the inset: FL – Ferm i level, VB – Valence band, L-distance of the acceptor sheet from the QW . (d) Transm ission (top) and PL spectra (bottom) for a Cd_{0.99}M $n_{0.01}Te QW$ with a 150A thick cap layer. Neutral and charged exciton lines dom inate the spectra indicating a low carrier density.

unambiguously determined from the circular polarization of the charged exciton absorption in Faraday con guration: Due to the same signs of the electron and hole q-factors, the positively charged exciton is observed in polarization [?] while the negatively charged exciton is observed polarization [?]. In Fig. 1a, the lower energy line in + obeys the selection rules for positively charged excitons, which shows that free holes are present in this CdTeQW close to the surface. Note that no nitrogen acceptors were introduced into this sam ple. The opposite polarization rule was observed in a CdTeQW identical to the previous one but with a thicker (1000A) cap layer (Fig. 1b). The weak intensity of the X line indicates a low concentration of electrons. Hence we conclude that we have a weak residual doping, which is n-type and accounts for the low electron density in the deeply buried QW, while the hole gas with a higher density in the QW close to the surface has a di erent origin.

The presence of a carrier gas was also evidenced in $Cd_{1 \ x} Mn_x Te \ QW \ s$. In samples with a thin cap layer, the so-called Moss-Burstein shift between the absorption (or re ectivity or PLE) line and the PL line indicates a large density of carriers in the QW (Fig. 2a, b). In the

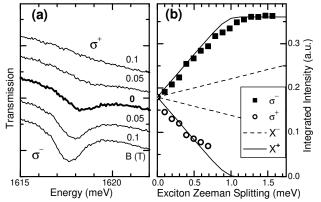


FIG. 3: (a) Transmission spectra, in magnetic eld, for a $C d_{0.995}M n_{0:005}Te QW$ placed 250A below the surface of the sample. M easured hole concentration is 2 10¹¹ cm². (b) Integrated intensity of transmission line versus Zeem an splitting in both circular polarizations (points) and results of calculation for electron (solid line) and hole gases (dashed line).

case of band-to-band transitions, the Moss-Burstein shift is equal to the sum of the kinetic energies of electrons and holes (which are involved in the excitation process) at Ferm i wavevector $k_{\rm F}$, so that it can be used as a tool for m easuring the carrier density. For a better accuracy, the Moss-Burstein shift was measured at a magnetic eld such that the carrier gas was fully polarized: Then the Moss-Burstein shift measured in ⁺ polarization is twice its value at zero eld. Note the change in re ectivity line in agreem ent with the cap layer thickness [?]. The carrier density was then calculated assuming an e ective electron massm_e = 0:1m₀, and an in-plane hole massm_h = 0:25m₀ [?]. We estim ate that the relative carrier concentration is then determ ined to within a few %, while its absolute value is accurate to within a factor of two due to residual excitonic e ects [?]. The determ ination of the carrier density from the Moss-Burstein shift makes no assumption on the nature (electrons or holes) of the carriers. However, once the density of carriers is known, their sign can be deduced from the value of the magnetic eld necessary to fully polarize the carrier gas. Full polarization is witnessed by the vanishing of the charged exciton absorption in + polarization (Fig. 3). Due to the giant Zeem an e ect, characteristic for diluted m agnetic sem iconductors (DMS), com plete spin polarization of a hole gas of density 2 $\,$ 10 11 cm $^2\,$ in a Cd_{0:99}Mn_{0:01}TeQW is achieved when applying a magnetic eld as low as 0.1T. This eld is expected to be at least 5 tim es larger for the sam e density of electrons [? ?].

A set of sam ples with similar growth conditions, and almost identical structure, allowed us to investigate the in uence of the cap layer thickness on the QW hole density. In this series of sam ples, contrary to sam ples shown in Fig.1, we used a thin layer of nitrogen doped barrier material, 1000A below the QW, to screen any spurious e ect from the interface with the substrate. The hole density (as deduced from the Moss-Burstein shift) signi cantly increases when the thickness of the cap layer decreases from 600 to 250A (Fig.2c). This reinforces the idea that the origin of the hole gas is not linked to a residual doping of the material, but is due to the presence of electron traps (acceptors) on the surface. We can calculate the hole density expected in the QW assuming a high density of acceptor states on

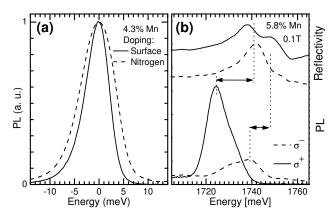


FIG.4: (a) Zero eld PL spectra of a single C $d_{0.957}$ M $n_{0.043}$ Te QW at 42K.The QW is depleted from carriers using blue light illum ination.One sample (dashed line) was grown at 220 C and doped with nitrogen.The other one was doped from the surface states (250A cap layer) and grown at 280 C.Both have the same M n content and carrier density in the dark.The spectra are norm alized and their positions are shifted. (b) PL and re ectivity spectra in circular polarizations at 0.1T and 1.7K for a sam ple with 5.8% M n in the QW.

the surface, with the energy position of these surface states as the only adjustable parameter. If we de ne this position by the distance E between the acceptor state and the level con ned in the QW, the hole density is mostly determined by the e ect of the electric eld between the QW and the surface (see the inset in Fig. 2c), i.e. we can neglect sm all contributions such as the change of con nement energy within the QW, the kinetic energy of con ned carriers, or the valence band shift due to the sm all am ount of M n in the QW. Then the QW hole density sim ply writes $p = ""_0 E = (eL)$ where " (= 10) is the dielectric constant of the cap m aterial, "_0 is the permittivity of vacuum, e is the electron charge, and L is the thickness of the cap layer. A good t is obtained if we take E = 90 m eV (dashed curve in Fig. 2c).

This value should be considered with care. First the carrier density is probably higher than the value we determ ine optically, since illum ination tends to decrease the carrier density, even when using a low intensity at photon energy smaller than the barrier gap. In addition, one should keep in m ind that -due to residual excitonic e ects - the M oss-B urstein shift determ ination is not too precise on the absolute value of the carrier density [?]. A lso, a drop of the carrier density is observed on the sam ples with a very thin cap layer (below 200A). The decrease is dramatic in the two sam ples grown with L = 150A, where the free exciton is observed in transmission (Fig.2d), so that we estim ate the carrier density to be smaller than 10¹⁰ cm² [?]. Further studies are needed to elucidate the origin of this sharp drop.

The main result is that we obtained hole densities exceeding 2 10^{11} cm² in the QW s with a cap layer thickness of 250A without using in purities. The presence of holes probably also explains PL spectra observed in nom – inally undoped parts of gradually doped sam ples [?]. We show now that this allow s us to increase the growth tem –

Undoped samples have been shown to exhibit sharper lines when grown at higher temperatures [?] due to reduction of interface roughness. In doped samples other cases of broadening can operate. However in gure 4a we compare PL spectra of a nitrogen doped sample grown at 220 C, and of a sample doped from the surface states and grown at 280 C. Both samples contain 4.3% M n in the QW, and identical carrier densities in the dark. We present spectra measured in zero magnetic eld and under blue illum ination in order to deplete the QW from hole gas. Sharper lines are observed in the second sample.

Carrier induced ferrom agnetism was observed in those sam ples with 4.3% M n [?], with the same behavior in the nitrogen and surface doped sam ples. In addition, we can grow $Cd_1 \times Mn_x TeQW$ swith the x up to 9.3% and yet a signi cant hole density. As an example gure 4b presents the PL and re ectivity spectra in circular polarizations for a sample with 5.8% M n in the QW at magnetic eld of 0.1T, so that the hole gas is fully polarized. The shift in polarization can be attributed to disorder (Stokes shift). The shift in $^+$ polarization is signi cantly higher due to the presence of the hole gas and accompanying M oss-Burstein shift.

W e have no conclusive inform ation on the nature of the surface states involved in the form ation of the hole gas. The presence of acceptor states at the surface of $Cd_{1 x} Zn_{x} Te$ has been reported by Yang et al. [?] and attributed to the form ation of TeO $_2$. In order to control the form ation of oxides on the $C\,d_{1\ y\ z}$ M $g_y Zn_z Te$ surface, a 50A $\$ thick layer of am orphous tellurium can be deposited at {20 C right after the growth. We used two samples placed sideby-side on the substrate holder during the growth. Then one sample was removed from the MBE chamber, and the second one was heated up to 240 C for a few seconds in the vacuum, in order to re-evaporate the Te layer (as controlled by RHEED). No hole gas was present in the QW of the sam ple protected by the Te layer, while a hole density 2 10^{11} cm² was found in the QW of the sample without the Te cap. This suggests that surface oxides m ay indeed play a role in the form ation of the electron traps.

In conclusion, we demonstrate an e cient method for doping CdTeQW susing surface acceptor states. Hole densities in excess of 2 10^{11} cm² in the QW have been measured by optical spectroscopy. The investigated mechanism was applied to obtain samples containing up to 9.3% M n in the QW with a signi cant hole gas density. E cient doping can be achieved without the technological restrictions arising from incorporating nitrogen in purities into the structures. We can therefore use higher temperatures for the growth of the samples (and further processing) and obtain a hole gas in deeper quantum wells or quantum wells with a higher M n content.

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